Investigations of RF Induced Burnout in Microwave Mixer Diodes: A Continuing Study

G.E. Morris, G.A. Hall, C.F. Cook and V.J. Higgins. "Investigations of RF Induced Burnout in Microwave Mixer Diodes: A Continuing Study." 1974 S-MTT International Microwave Symposium Digest of Technical Papers 74.1 (1974 [MWSYM]): 139-141.

Investigations of RF induced burnout in silicon point contact and Schottky barrier mixer diodes at X-band frequencies are presented. SEM observation of diode chip condition was made through a "window" in the package prior to burnout. Comparisons of photographs before and after burnout were used to determine subtle changes in chip topography.

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